
ATOM-PROBE TOMOGRAPHIC ANALYSES OF NIOBIUM SUPERCONDUCTING RF CAVITY MATERIALS

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Jim Norem

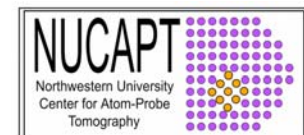
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**Now at Imago Scientific Instruments, Madison, Wisconsin*

*David N Seidman
13 July 2005*

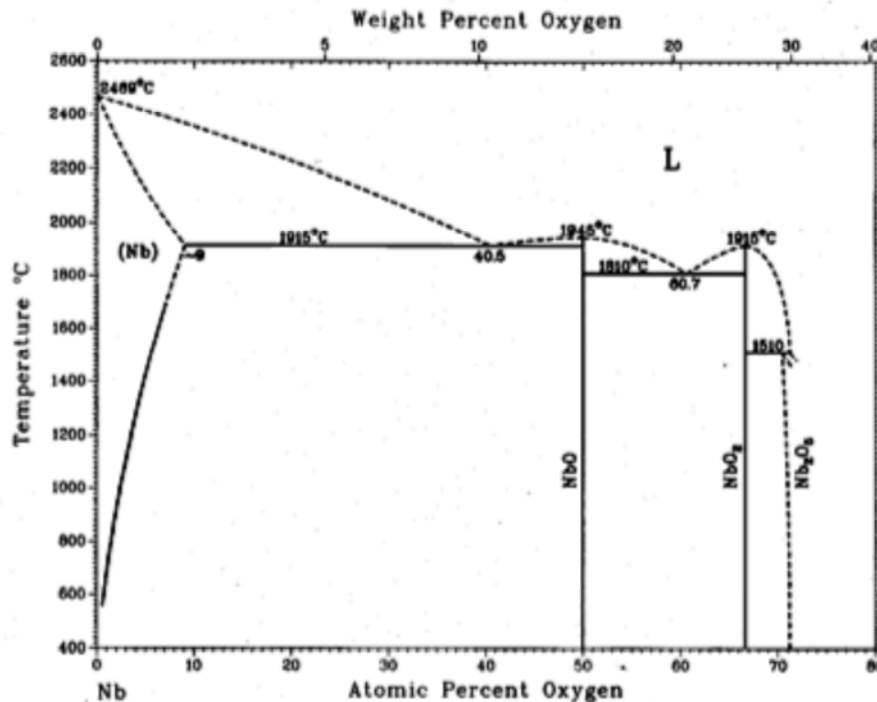


Agenda

- Background
 - Superconducting Nb rf cavities
 - Atom-Probe Tomography (APT)
- Specimen preparation
- Preliminary APT results
 - Three analyses (separate tips)
- Conclusions and next steps

The Nb-O phase diagram - a variety of different oxide phases can form

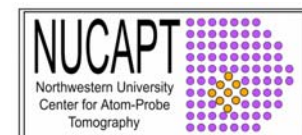
- NbO, NbO₂, and Nb₂O₅ are the thermodynamic equilibrium phases
- Other phases (e.g., Nb₂O₃ and Nb₂O) also reported
- Kinetic effects must also be considered



From Binary Alloy Phase Diagrams (2nd Ed.), ASM (1990)

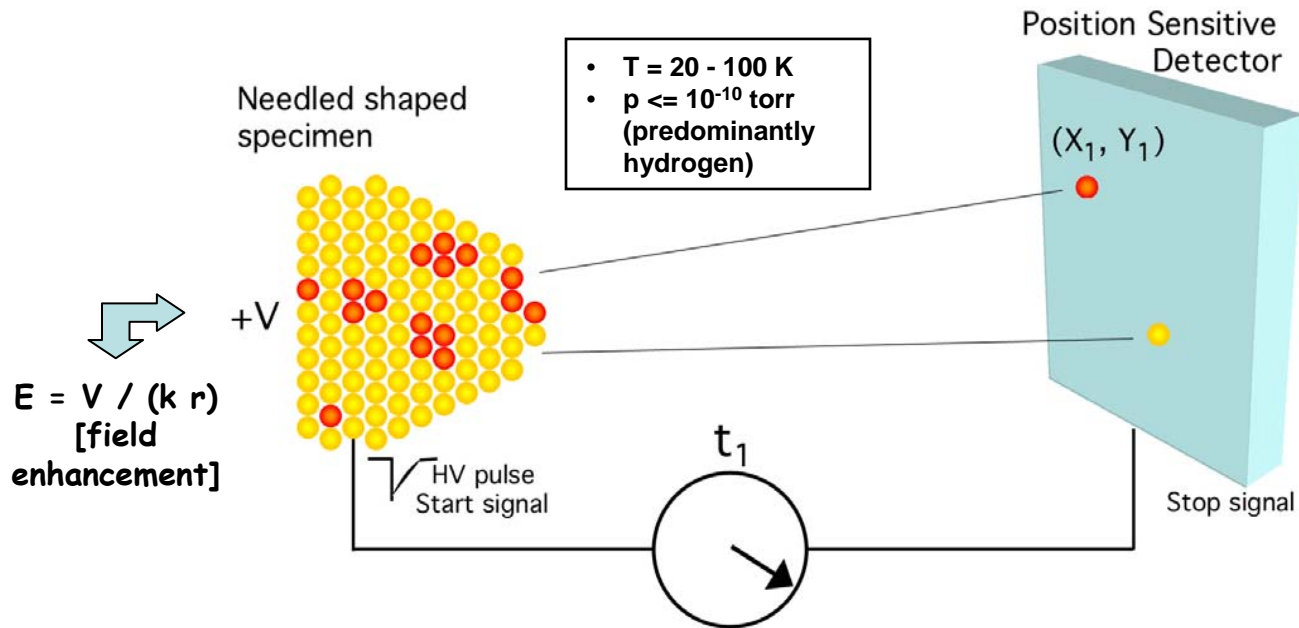
Phase	Composition (at. % O)	Pearson symbol	Space group	Prototype
(Nb)	0 to ~9	cI2(bar)	Im3(bar)m	W
NbO	50	cP6	Pm3(bar)m	NbO
NbO ₂	66.7	tI96	I41/a	
Nb ₂ O ₅	~71.4	mP99	P2/m	

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Atom-probe tomography (APT) - schematic

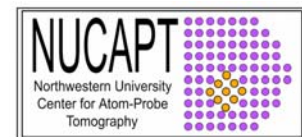
The time-of-flight (TOF) of each field-evaporated ion is measured simultaneously with the position of the impact on the 2D detector



$$\frac{m}{n} = k \alpha (V_{dc} + \beta V_{pulse}) \left(\frac{t + t_o}{d} \right)^2$$

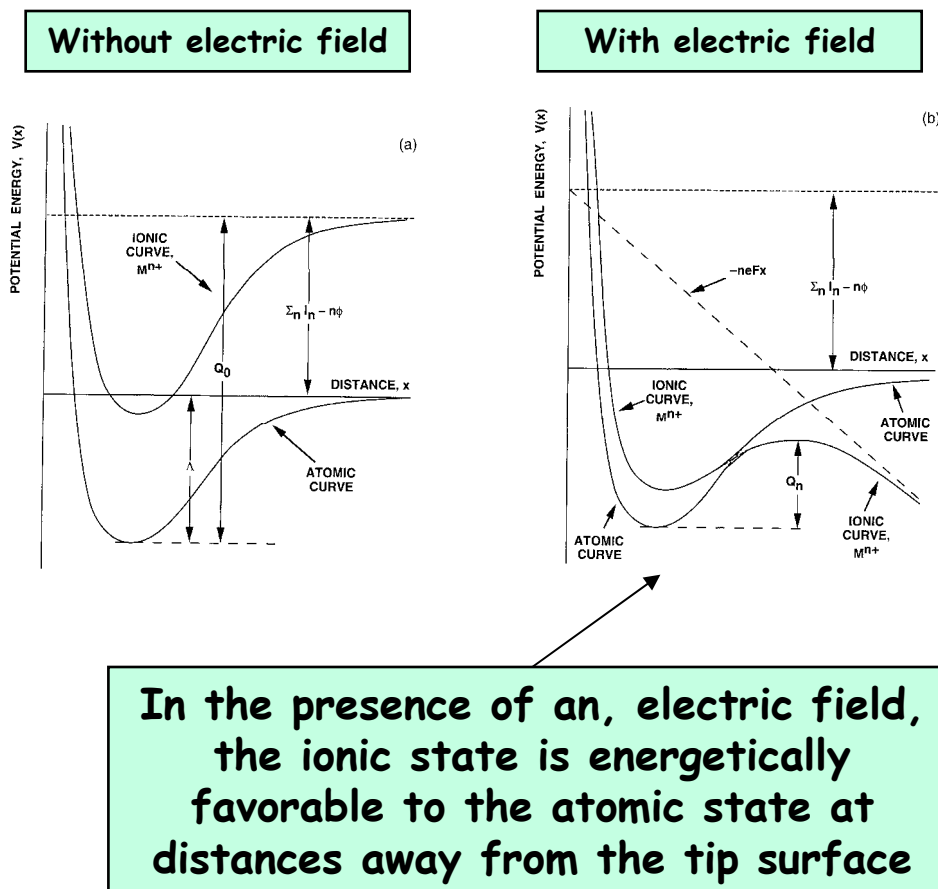
- Time of flight Chemical nature
- Impact Position Atom position on tip surface (projection microscope)

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Field evaporation - schematic

- A thermally-activated process involving the excitation of a surface atom over a Schottky hump in the presence of an electric field
 - In an atom probe, evaporation is controlled via the use of a high-voltage pulser, or high frequency (femtosecond) pulsing laser



NUCAPT's new local electrode atom-probe (LEAP) tomograph takes atom-probe microscopy to a new level

- Increased data collection rate (up to 72 million ions hr^{-1})
- Expanded specimen geometry capabilities
- Analysis volumes of, for example, $50 \text{ nm} \times 50 \text{ nm} \times 400 \text{ nm}$ ($= 10^6 \text{ nm}^3 = 10^{-3} \mu\text{m}^3$)

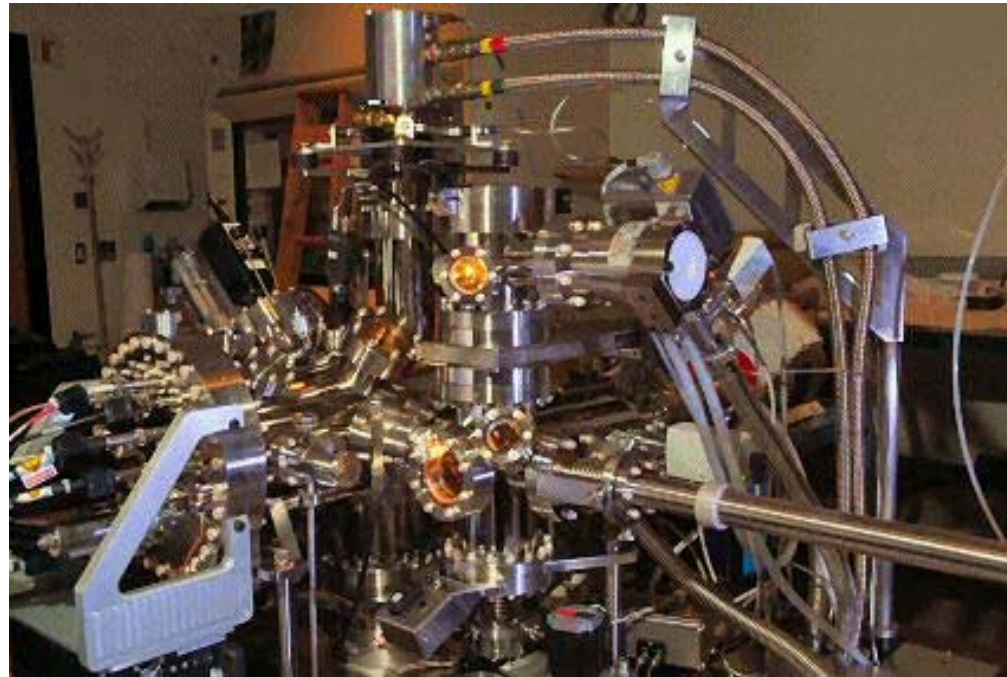
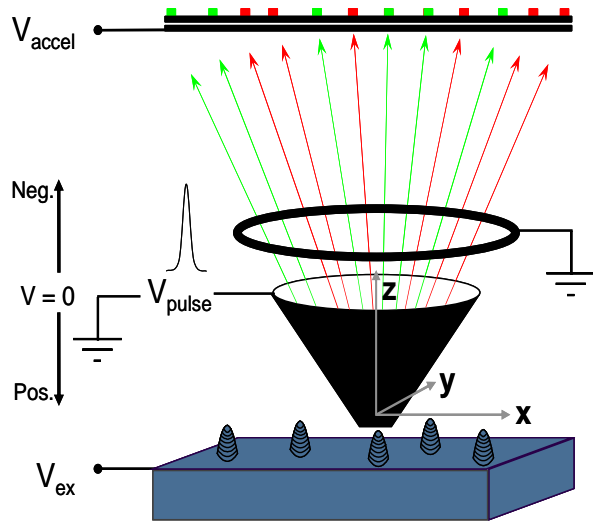
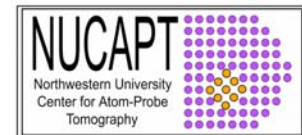


Figure courtesy of
Imago Scientific
Instruments

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NUCAPT's LEAP
Tomograph



Specimen preparation

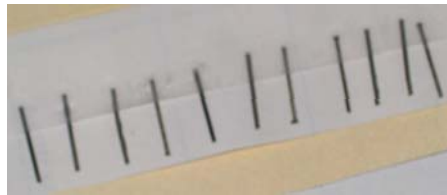
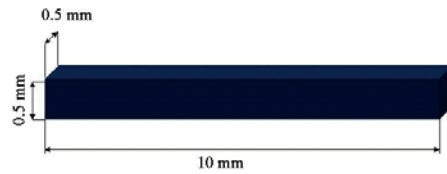
1. Electropolishing
 - 10% HF (48%) in 90% HNO₃ (68%)
 - DC voltage
 - "Drop off" technique
 - Keep things as clean as possible
 - Rinsing (UHP water)
 - Minimal time in air (stored in desiccator under dry N₂)

2. Buffered Chemical Polishing (BCP)
 - 1 : 1 : 2
HF (49%) : HNO₃ (68%) : H₃PO₄ (85%)
 - No voltage
 - Replicating the setup at FNAL

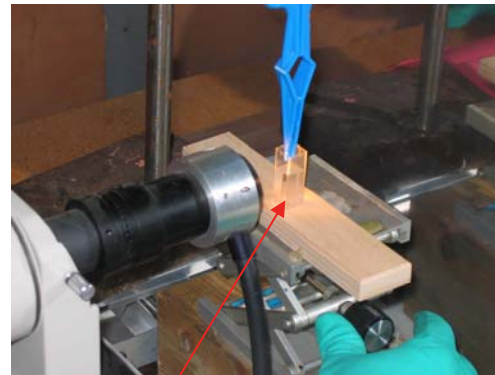
3. Focused ion beam (FIB) milling at ANL to be done soon
 - "Site-specific" specimen preparation

Specimen preparation - electropolishing and buffered chemical polishing

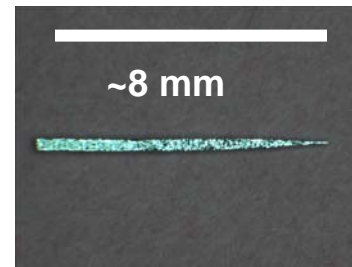
Step 1 - Machining Blanks (EDM at FNAL from Nb cavity material)



Step 2 - Polishing at FNAL



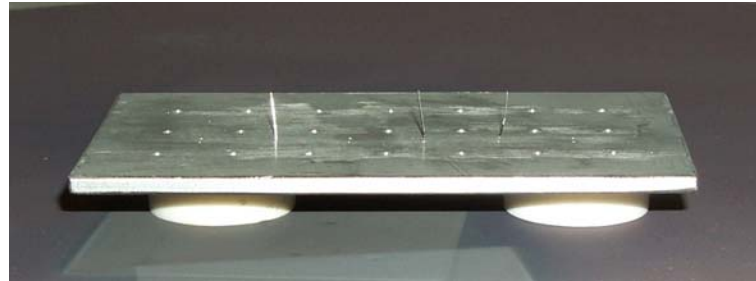
Rectangular
cuvette with
polishing
solution (BCP)



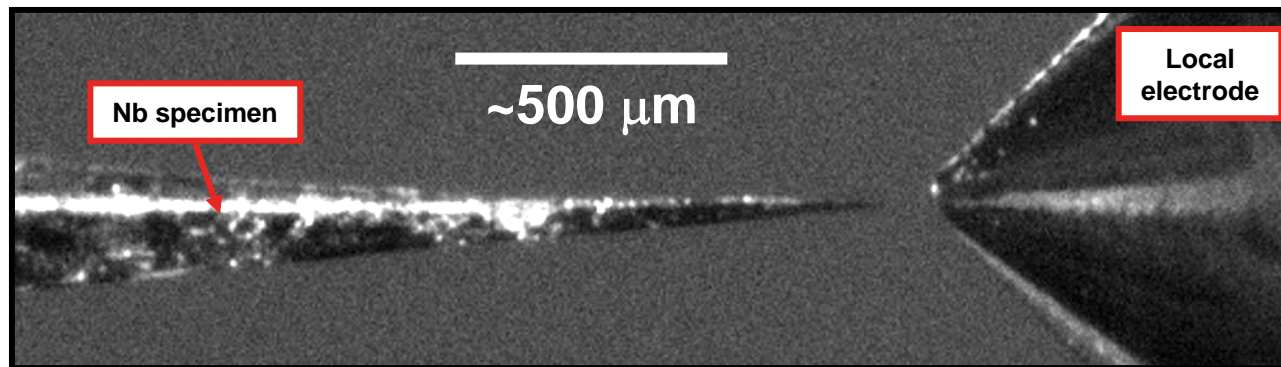
Stereo-
microscope

Specimen preparation - electropolishing and buffered chemical polishing

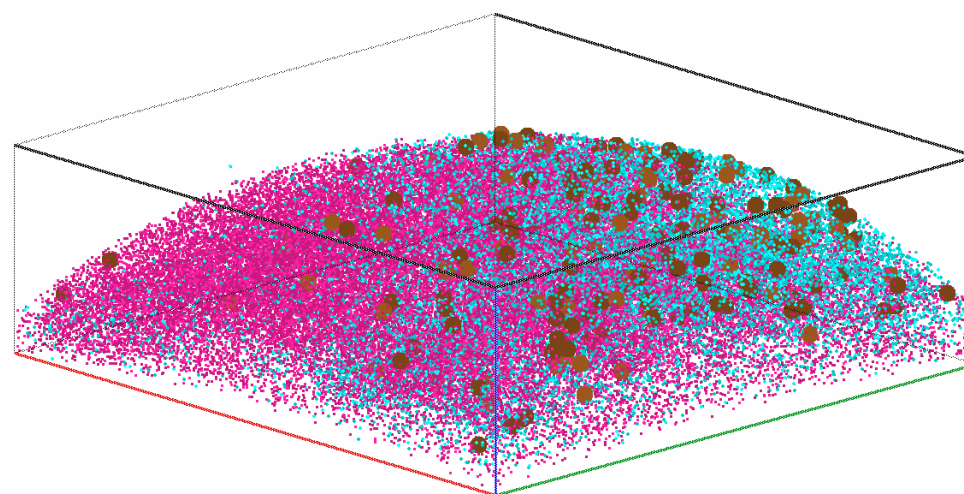
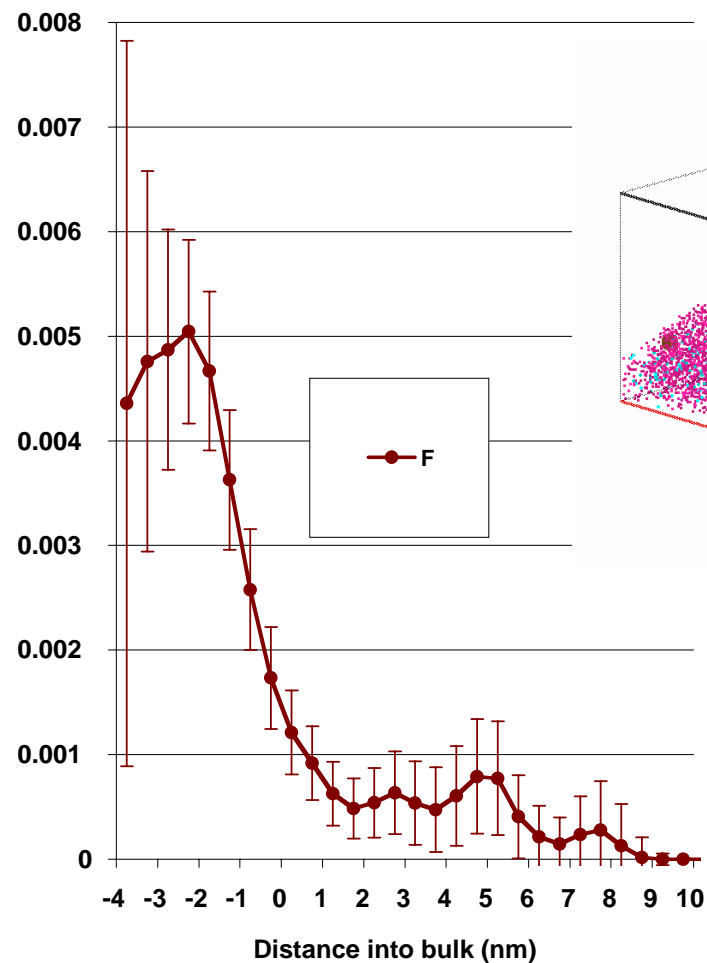
Step 3 - Heat treatment at FNAL



Step 4 - Alignment in the LEAP tomograph



Atomic sensitivity of the technique - individual fluorine atoms on and near the surface (propensity for the oxide)

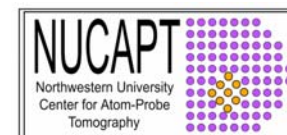


Direction of analysis

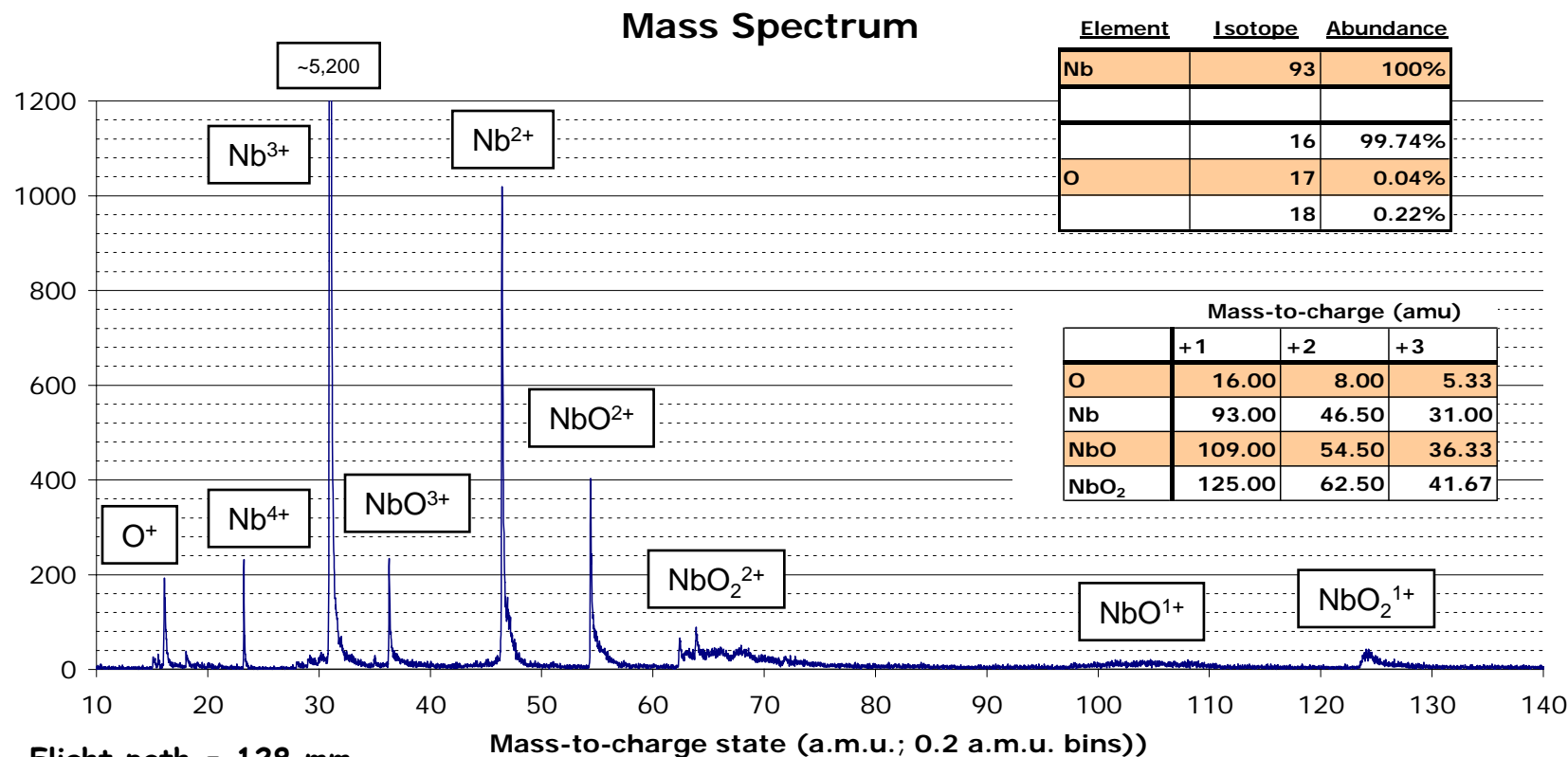
27 × 26 × 9
nm³
~95 k atoms

- Oxygen
- Niobium
- Fluorine

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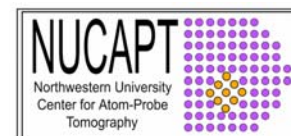


Complex mass spectrum - lots of complex ions

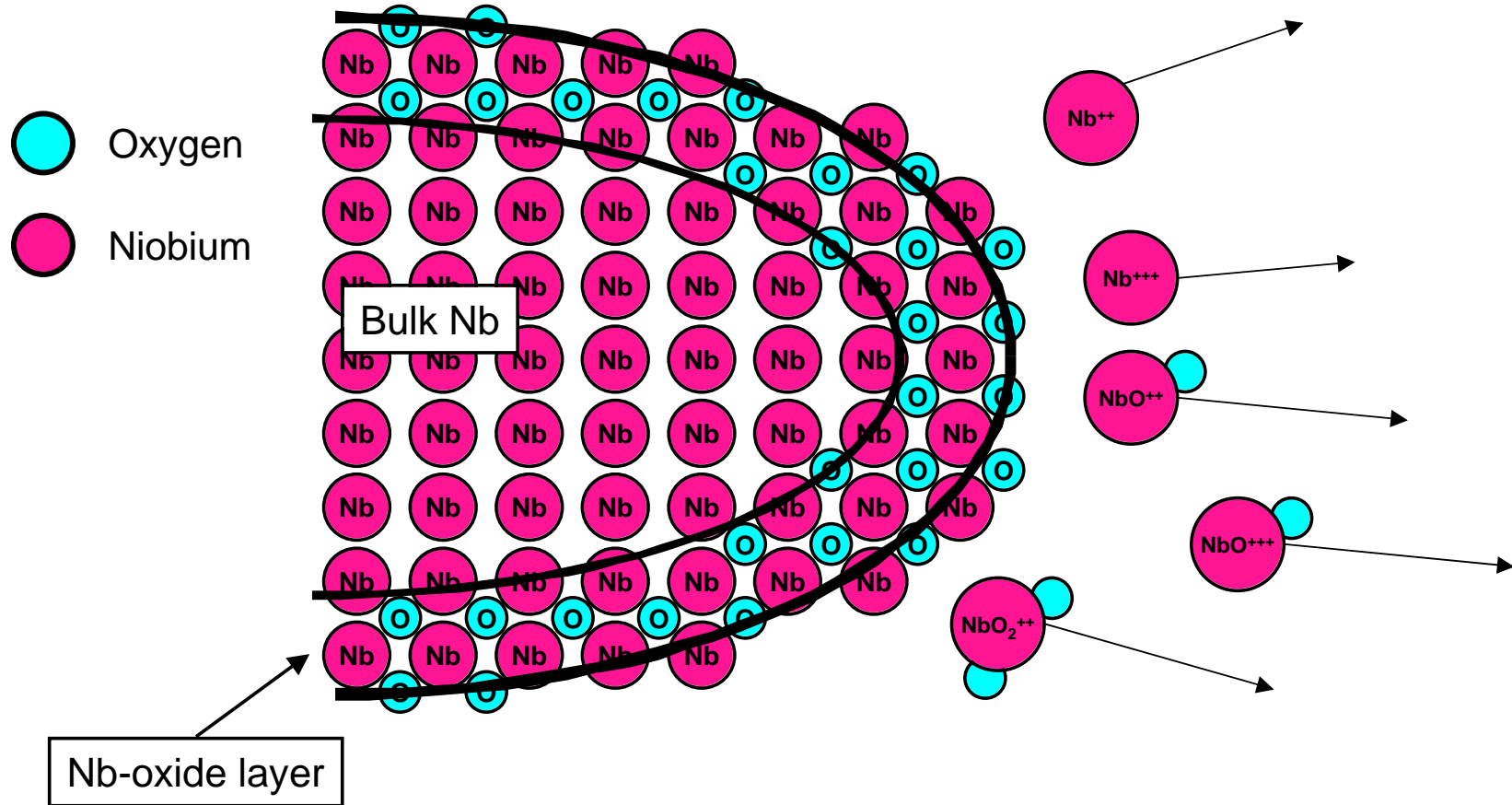


- Flight path = 128 mm
- Resolution $\approx 1/250$ (FWHM)
- T = 50K
- f = 15%
- p $\approx 8 \times 10^{-11}$ torr

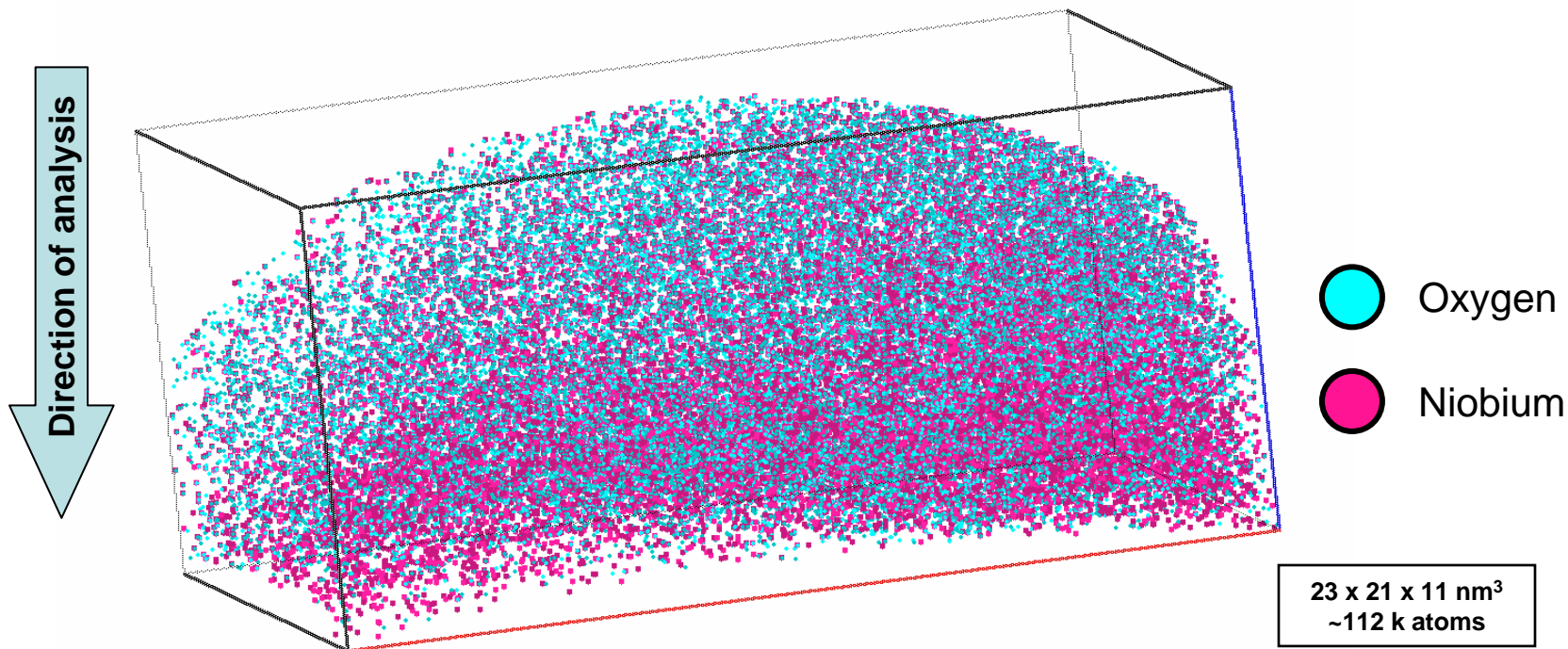
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Evaporation of complex ions (very schematic) - many different complex ions are field evaporated from the oxide layer of the tip

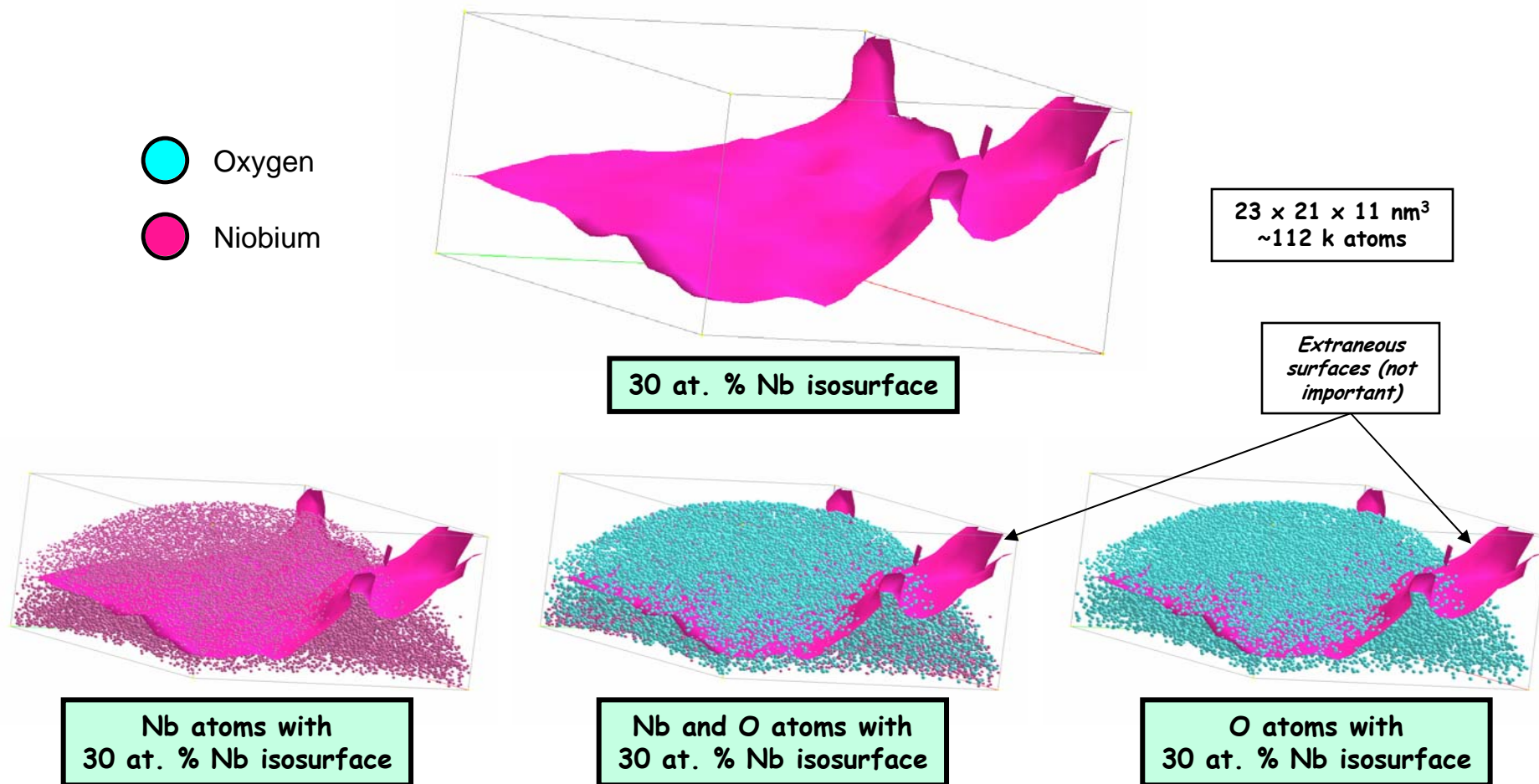


Atomic reconstruction of the transition through the oxide layer

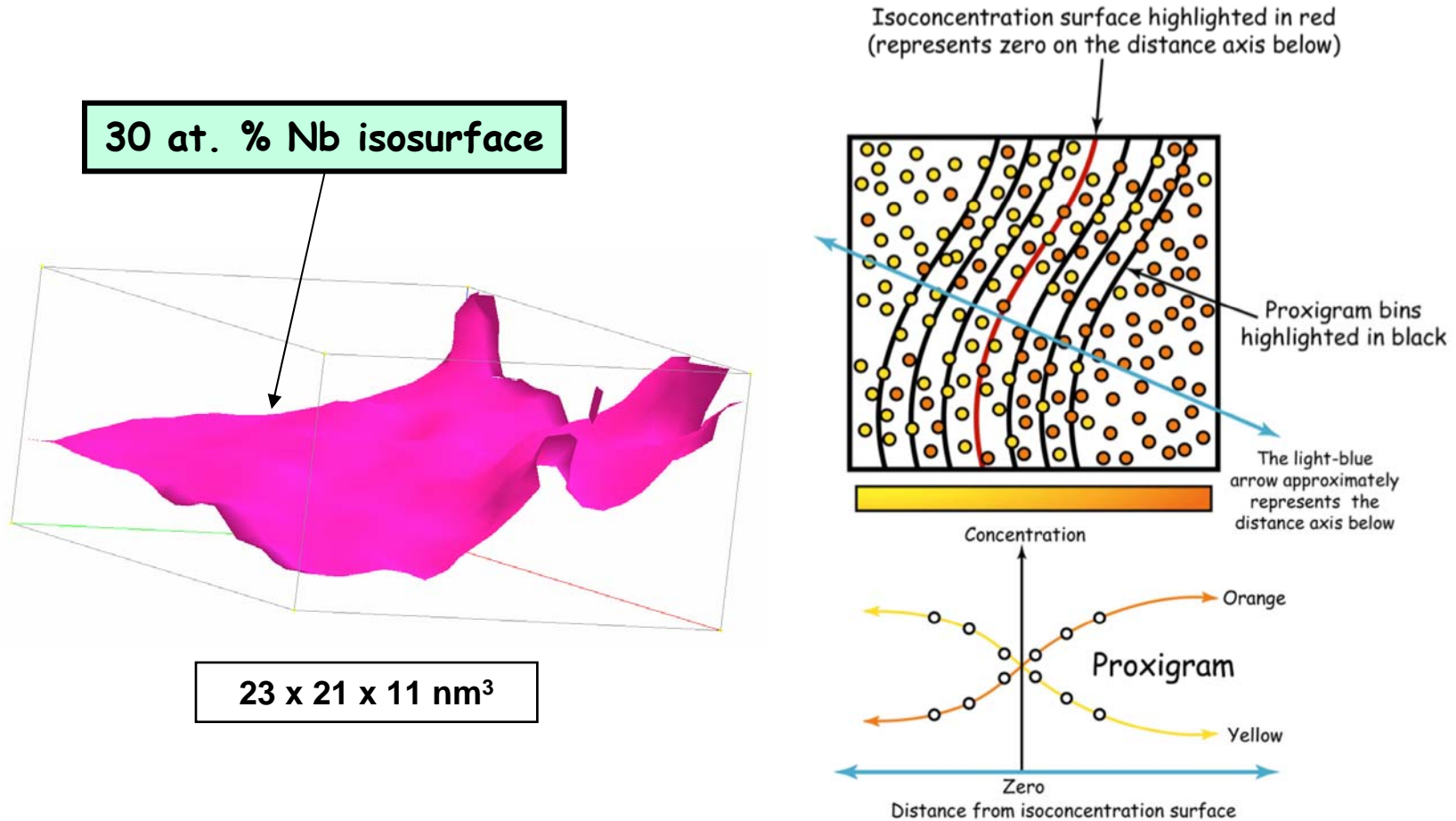


We see a clear transition from oxygen (cyan) to niobium (magenta) as we move along the analysis direction

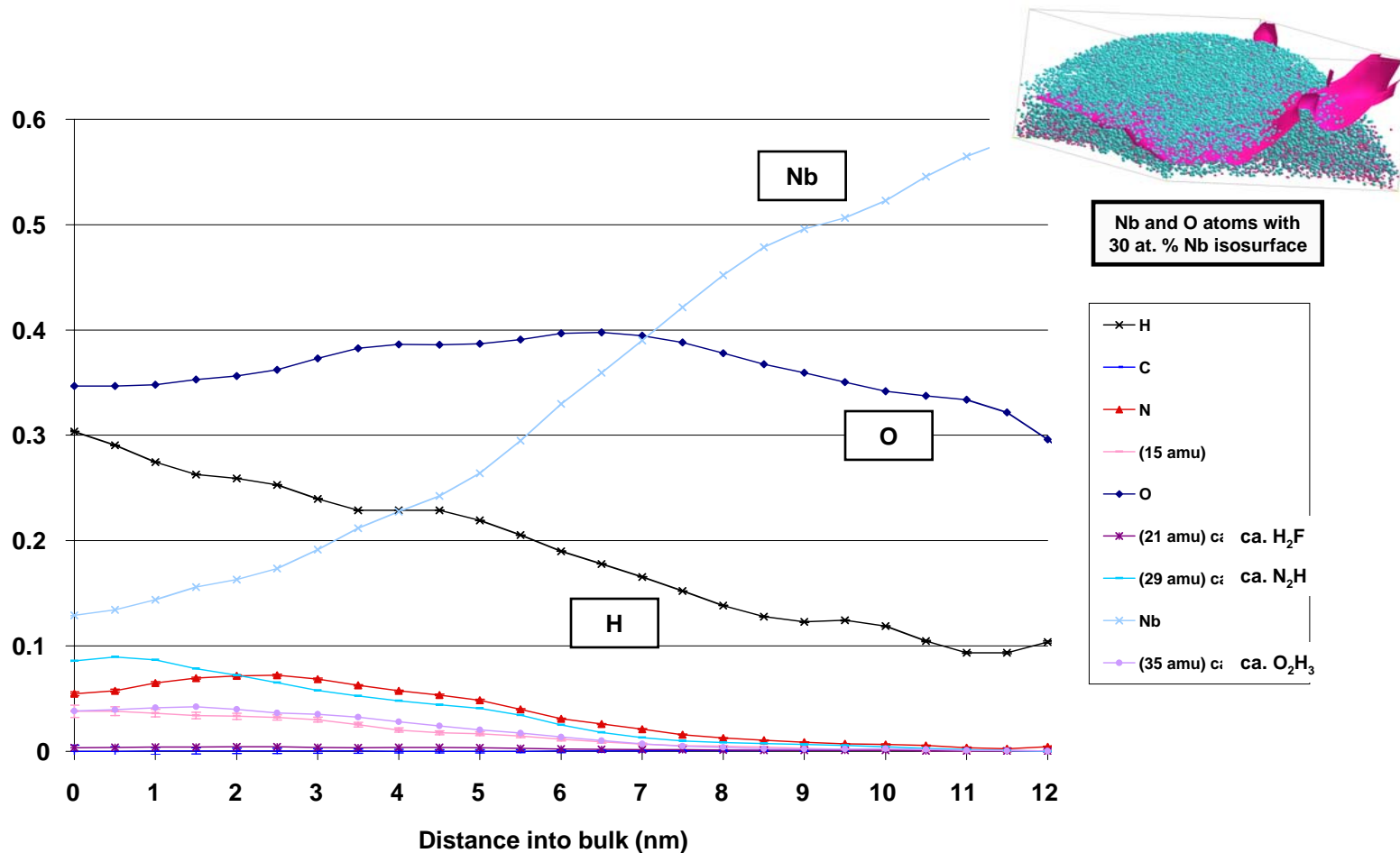
A 30 atomic percent Nb isosurface gives a better representation of the spatial gradients in atomic concentration



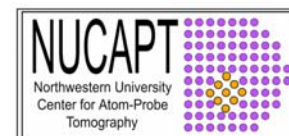
The proximity histogram (proxigram) allows for the determination of quantitative concentration profiles relative to the position of an irregularly-shaped interface



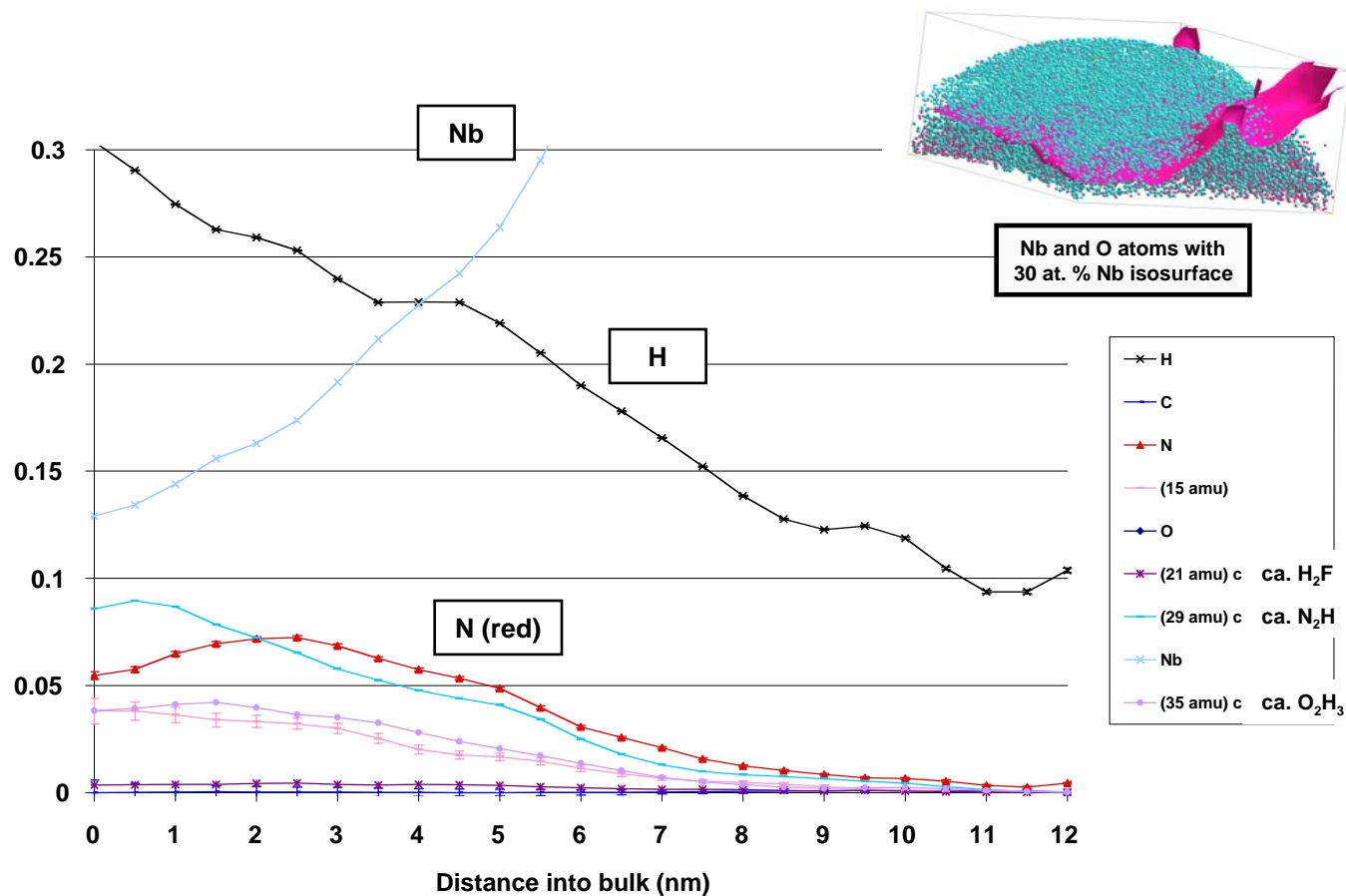
30 atomic percent Nb proxigram - we see the transition from oxygen to niobium



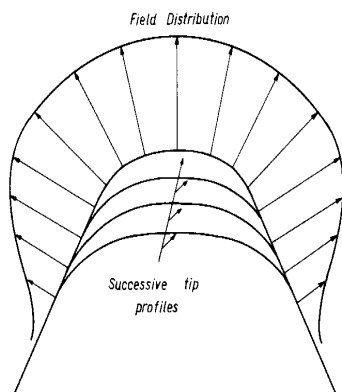
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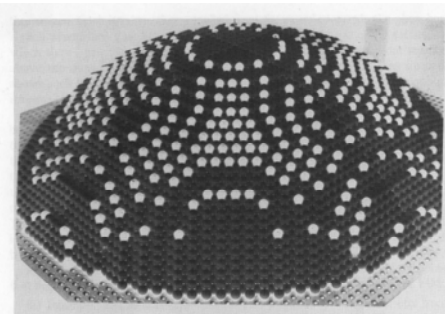
Hydrogen, residual gas atoms, and other "UFO" peaks make up nearly 50% of the ions collected



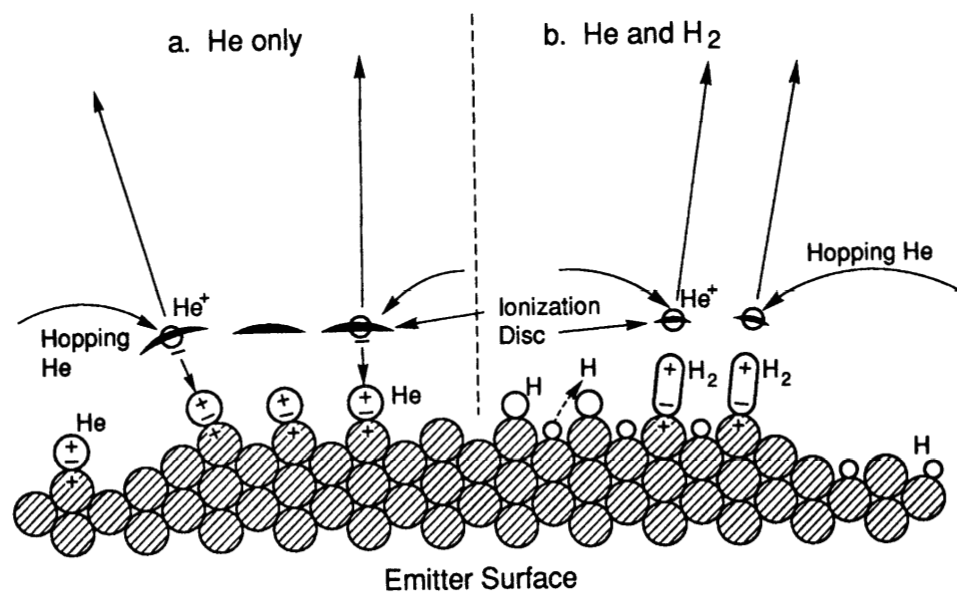
Hydrogen and residual gas atoms can come from "outside the specimen"



Electric field distribution on a atom-probe specimen (schematic)



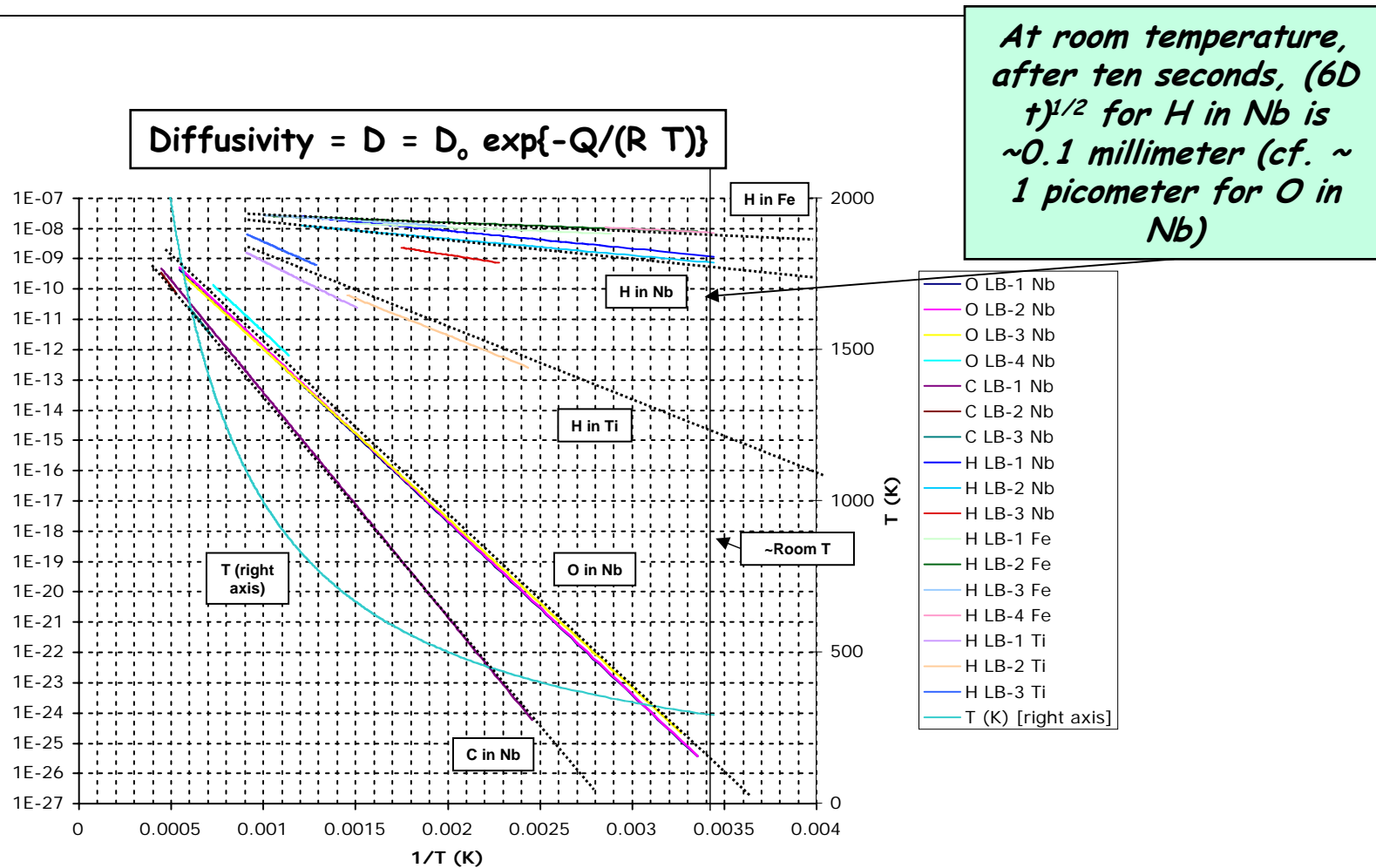
Ball model of an atom-probe tip surface (schematic)



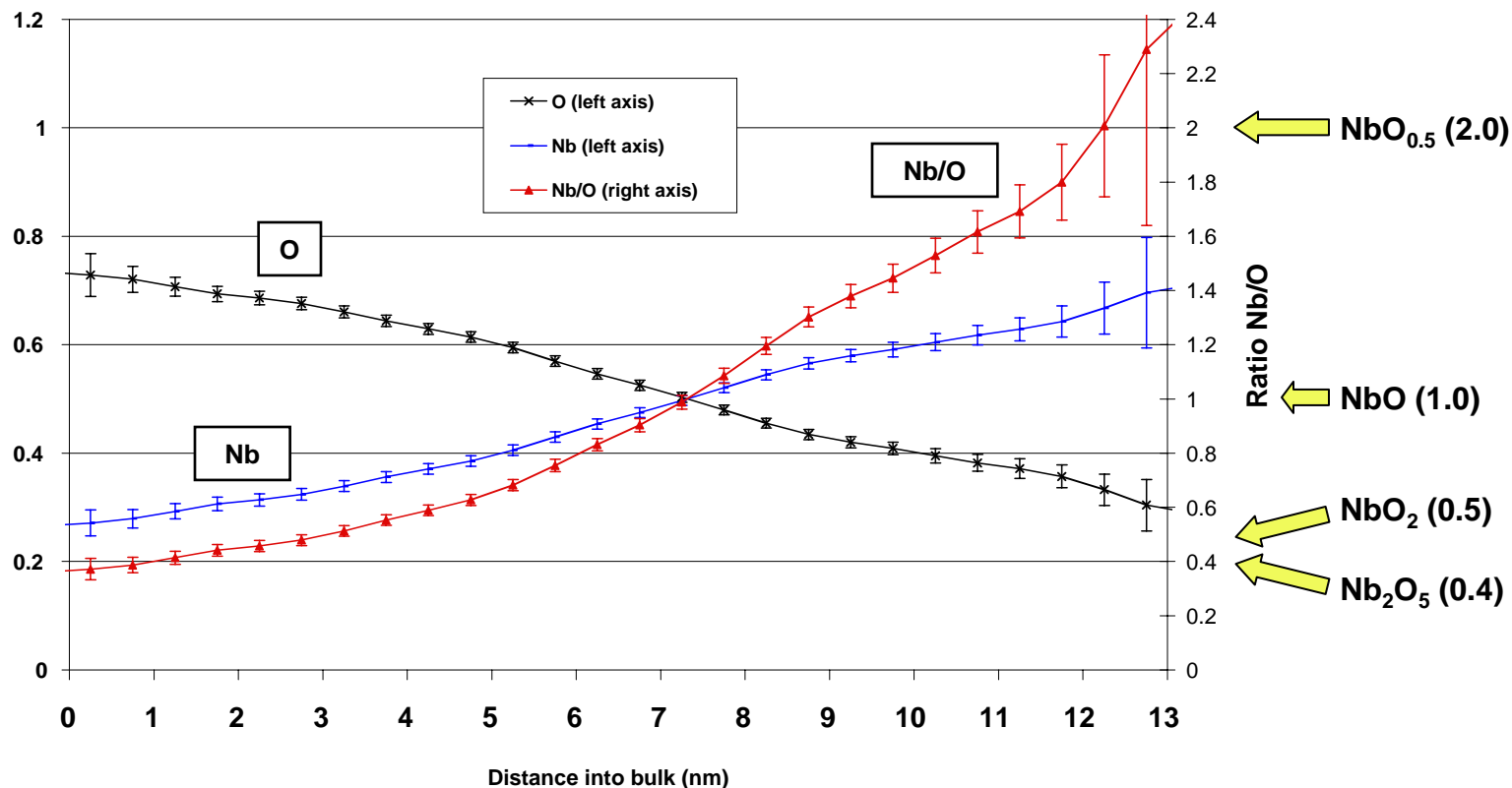
Field-ionization of gas atoms on an atom-probe tip surface

From Miller et al., (1996)

Hydrogen is extremely mobile in niobium (even at room temperature)

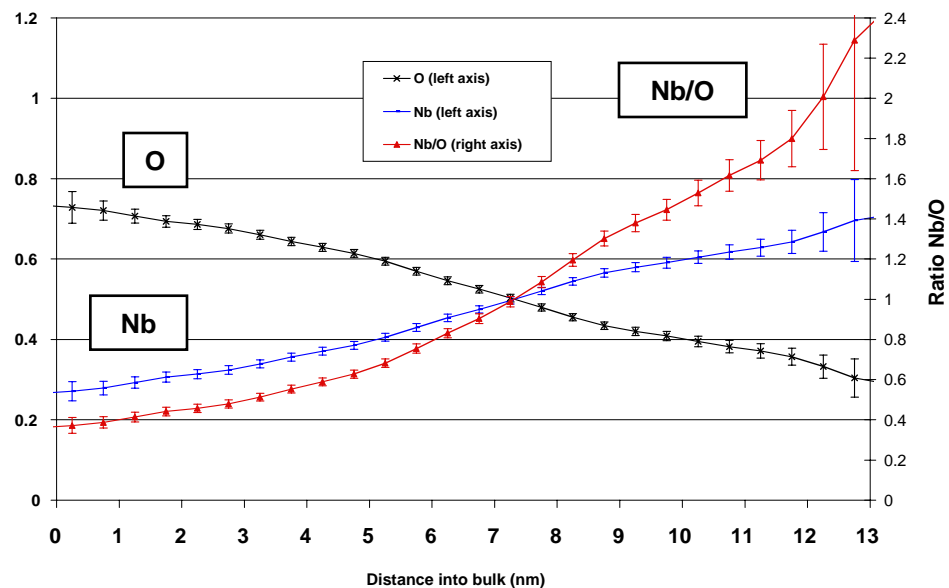
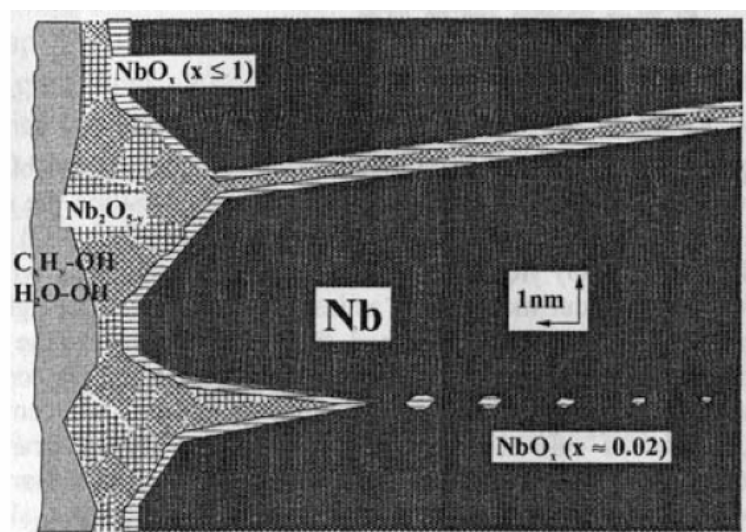


Removal of the hydrogen and residual gas atoms from the concentration gives a better picture of the transition through the oxide layer

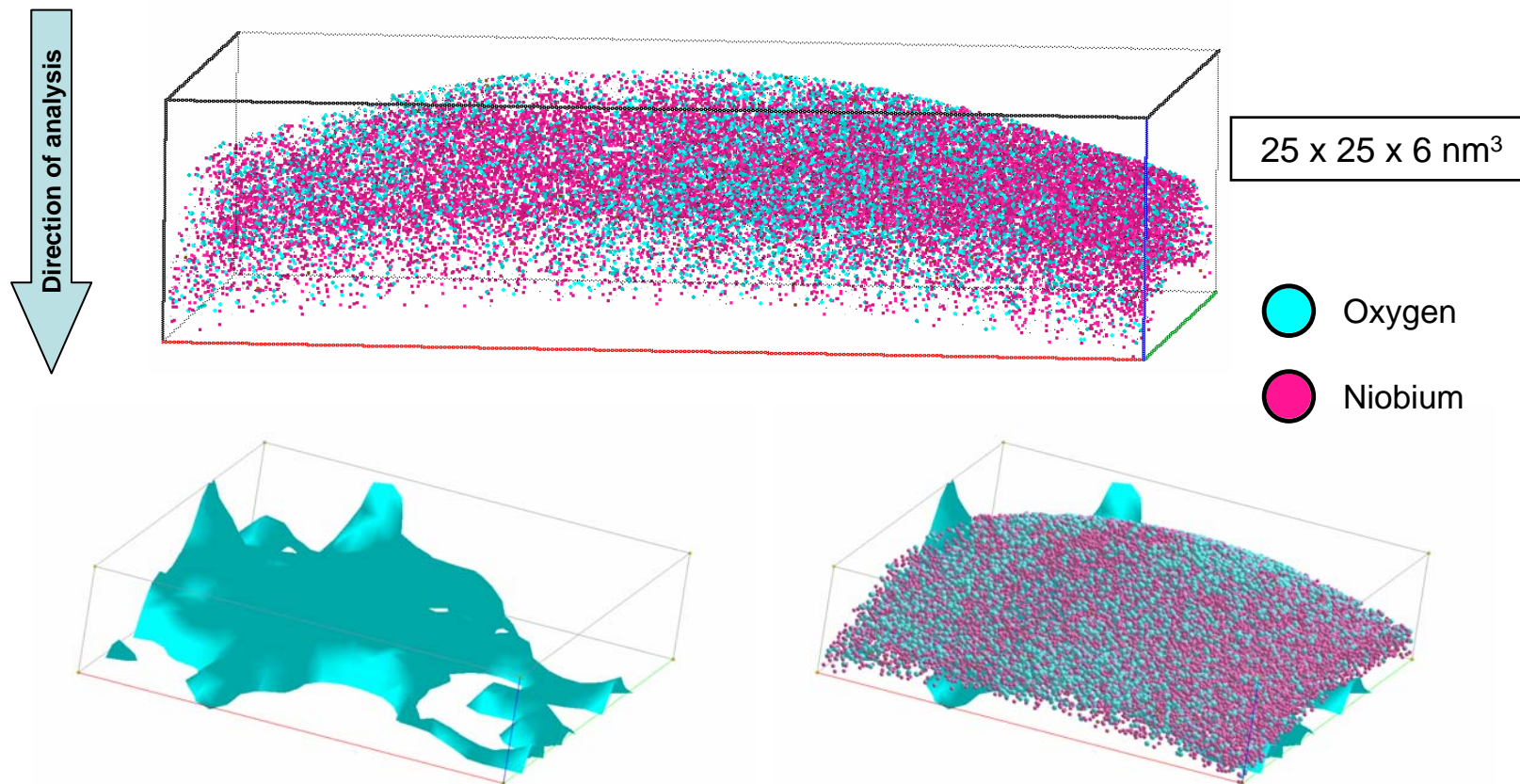


We see a clear and smooth transition from Nb₂O₅ to NbO_{0.5} (= Nb₂O)

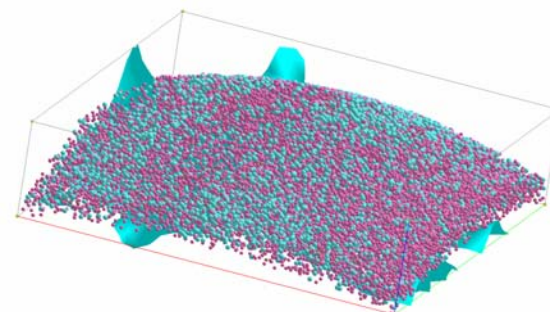
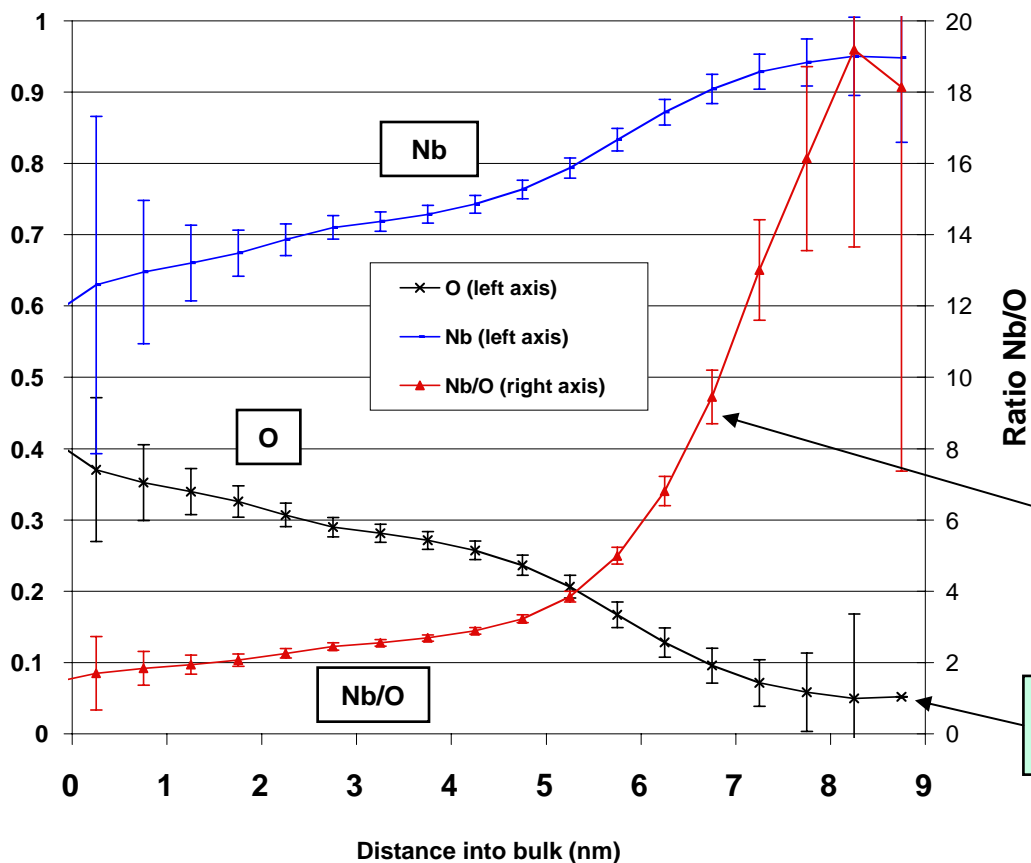
The profile corresponds, to first order, to the current models of oxide and suboxide formation on Nb



Second Nb analysis - more Nb-rich



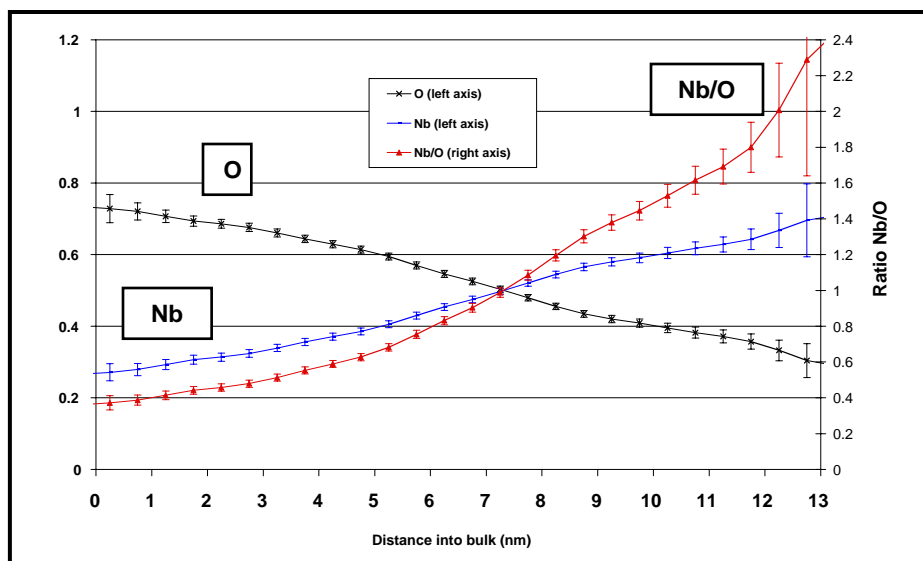
Second Nb analysis proxigram - a glimpse at the transition from oxide to Nb metal (?)



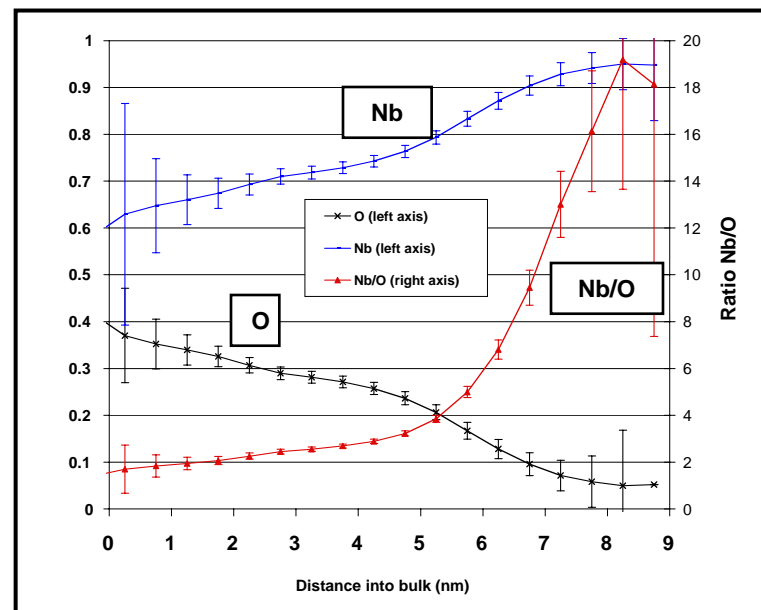
The transition from oxide to metal may be marked by a rapid increase in the ratio of Nb and O concentrations

Dissolved atomic oxygen in Nb metal (~5-10 at. %)

Second analysis ... a "continuation" of the first analysis

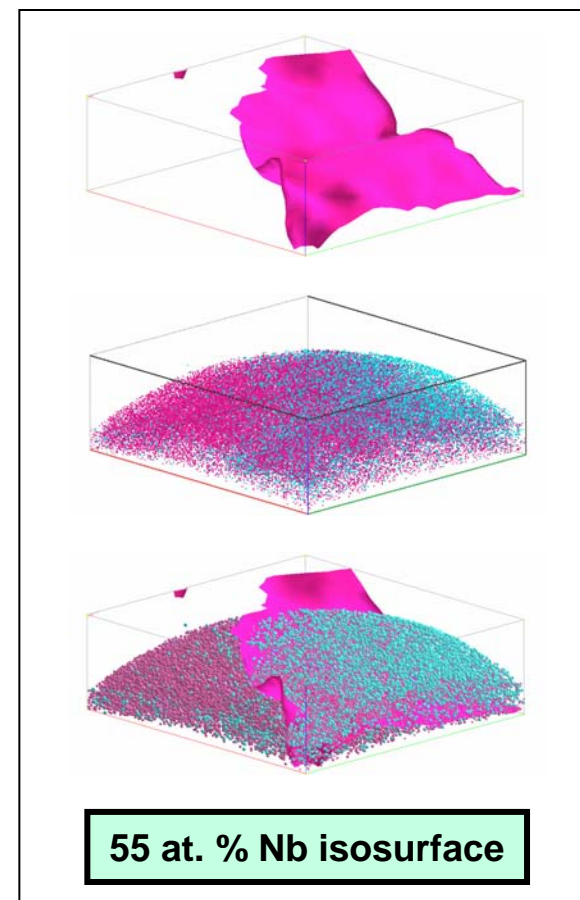
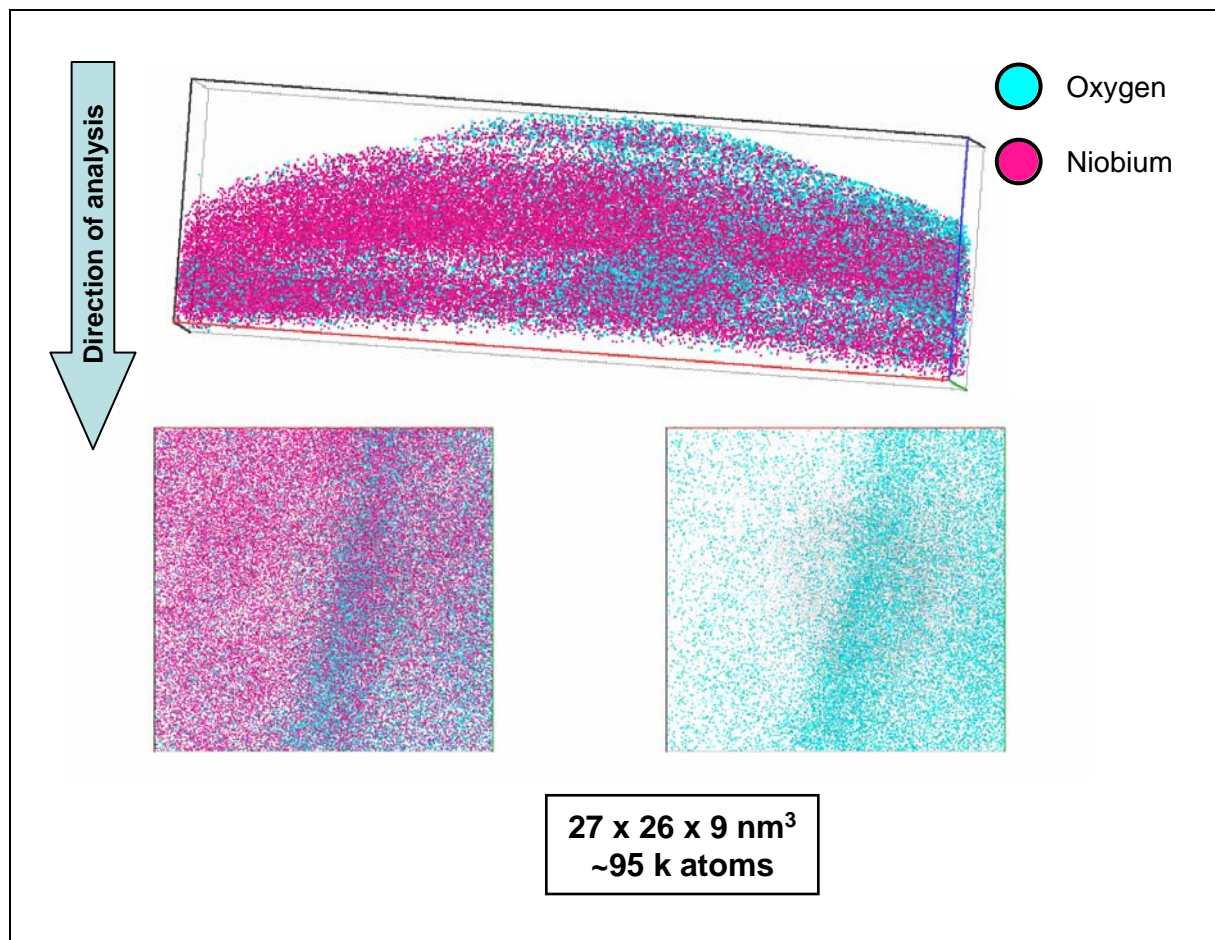


First analysis (Nb₂O₅ to Nb₂O)

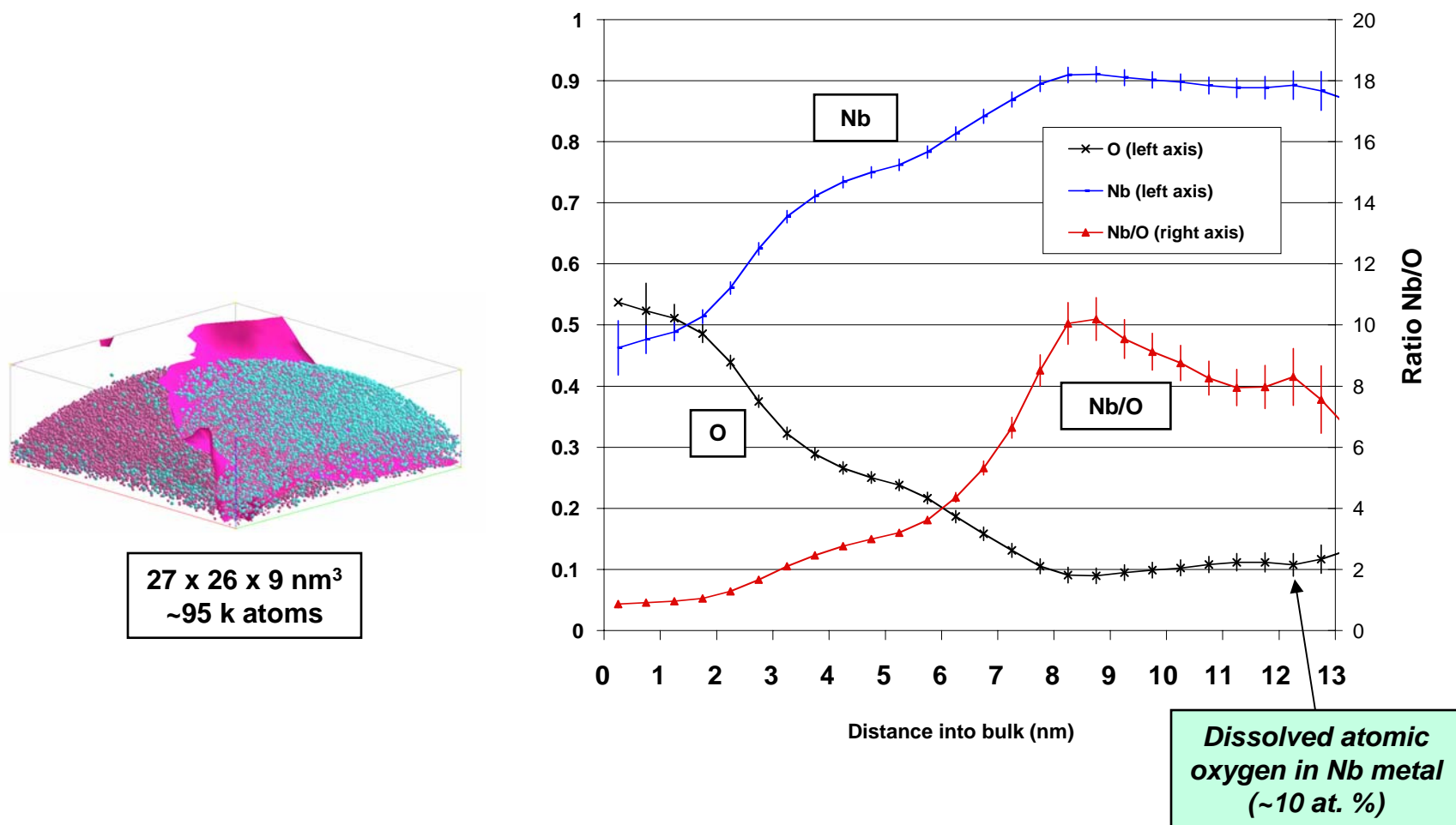


Second analysis (Nb₂O to Nb metal [?])

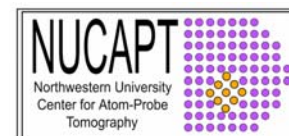
Third Nb analysis - an oxide metal interface



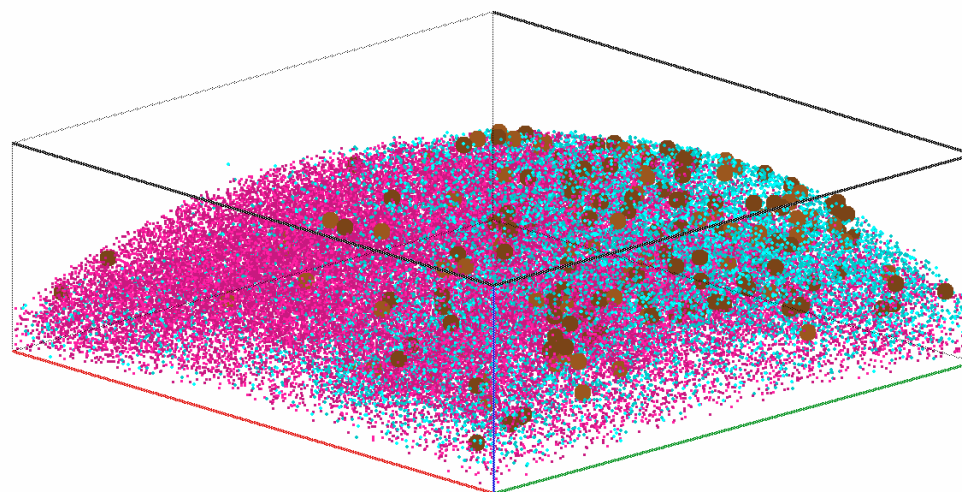
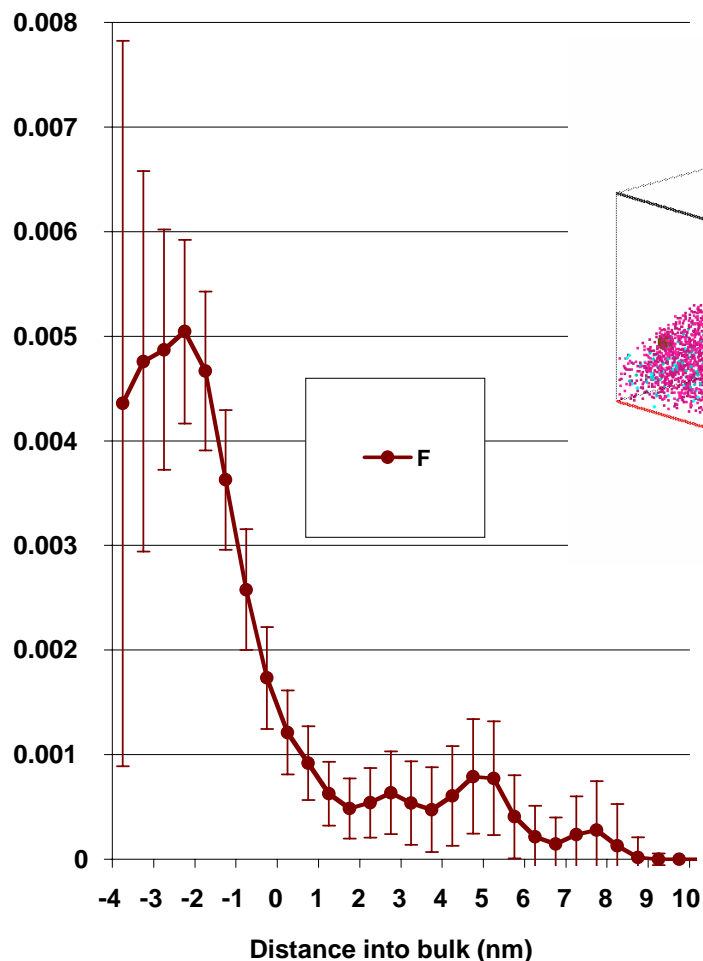
55% Nb isosurface and proxigram



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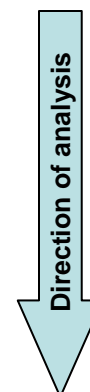


Atomic sensitivity of the technique - individual fluorine atoms on and near the surface (propensity for the oxide)



27 x 26 x 9 nm³
~95 k atoms

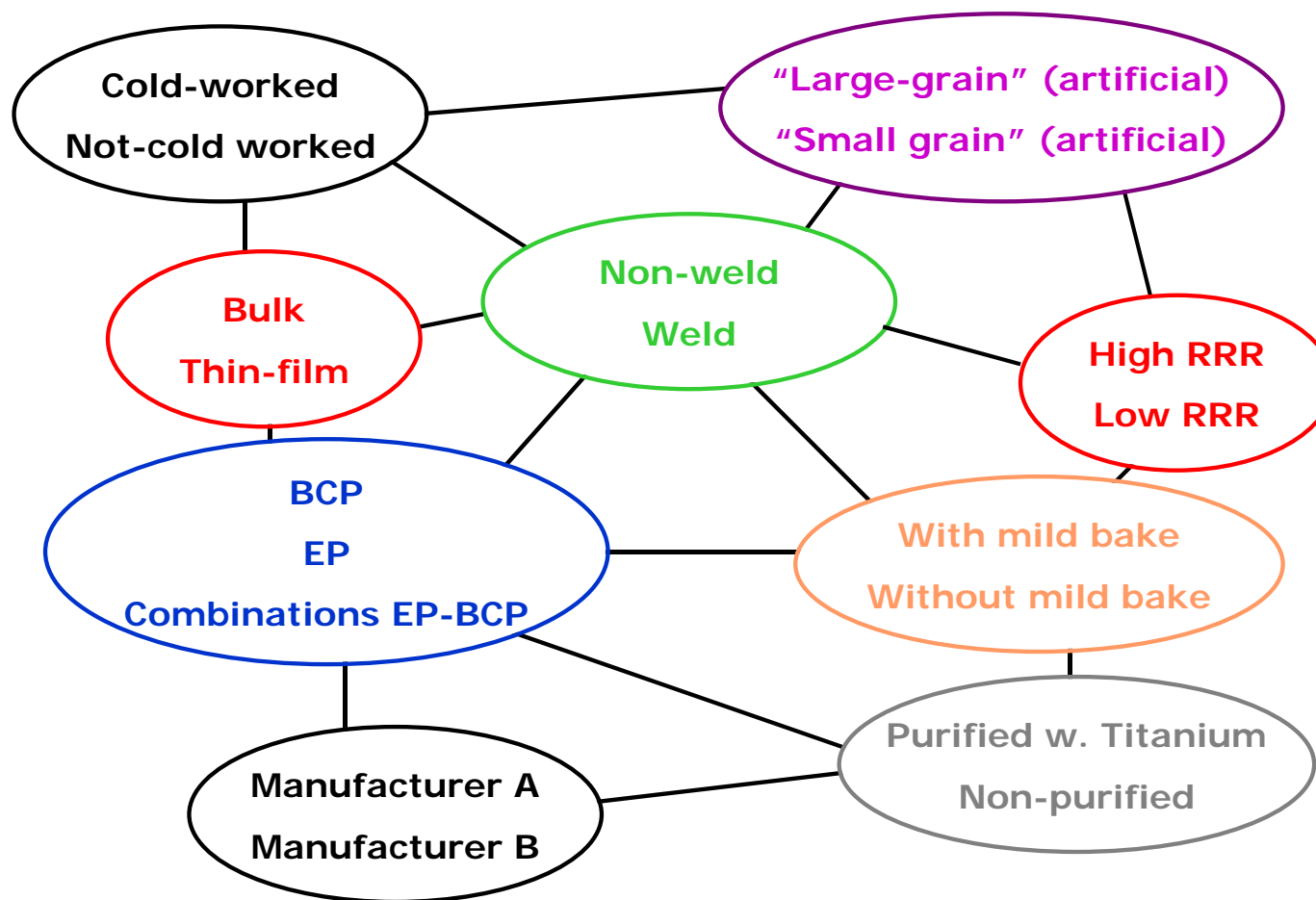
- Oxygen
- Niobium
- Fluorine



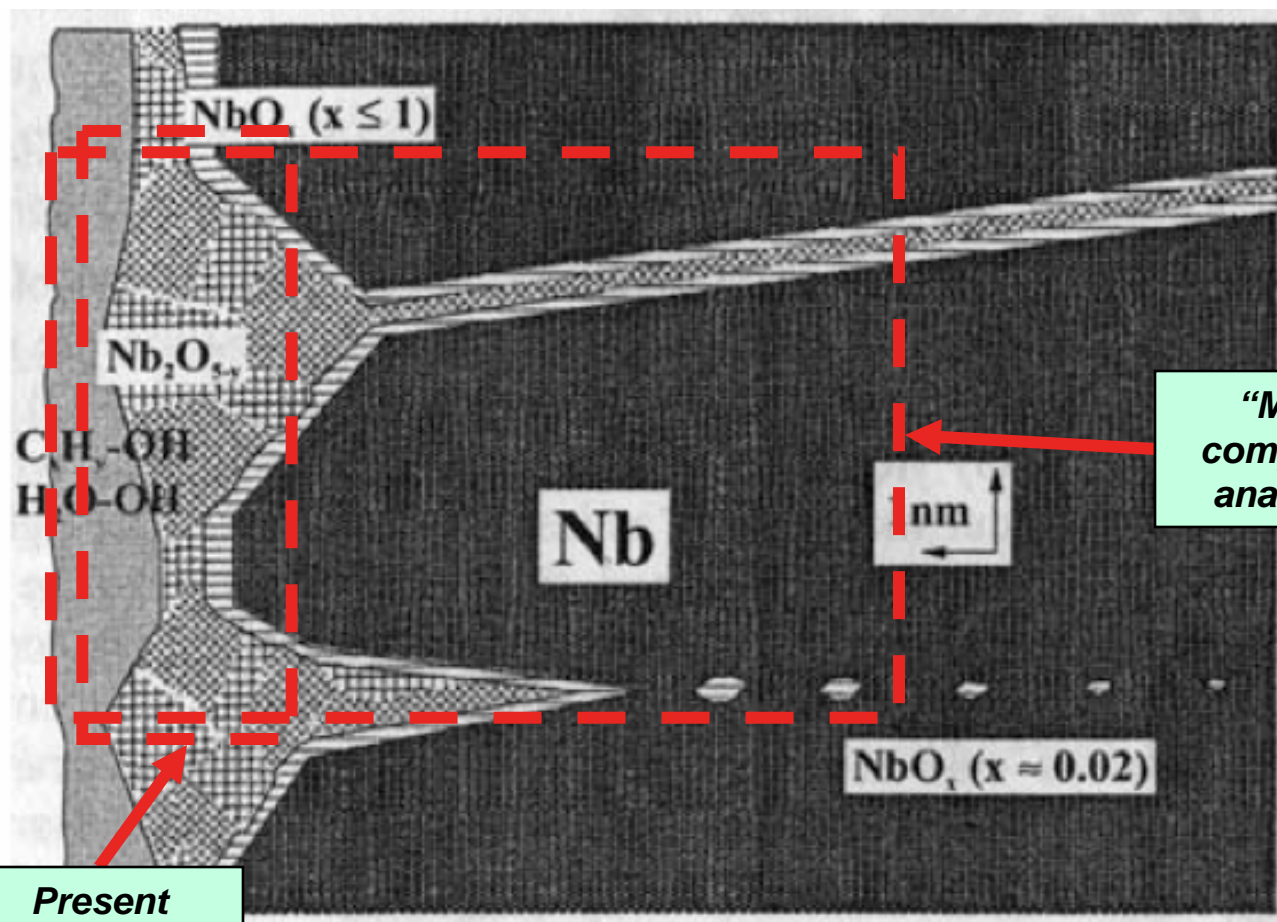
Conclusions and next steps

- Nanochemical, atomic scale analyses of the oxide surface and of the near-surface bulk niobium are being performed
 - “Smooth” transition from surface Nb_2O_5 to Nb_2O (and into the bulk Nb)
 - Ability to detect small number of contaminant atoms in the oxide surface and in the near-surface bulk niobium
 - Levels of oxygen in the near-surface bulk niobium (metal) of 5-10 atomic percent, which is consistent with bulk Nb-O phase diagram
- More analysis to come
 - Interpretation of mass spectra
 - Improved analysis conditions
 - Improved specimen preparation techniques (reliability and repeatability)
 - Focused ion beam (FIB) milling and/or femtosecond laser ablation
 - Many classes of samples

Classes of samples - effects of many, many variables on the atomic chemistry



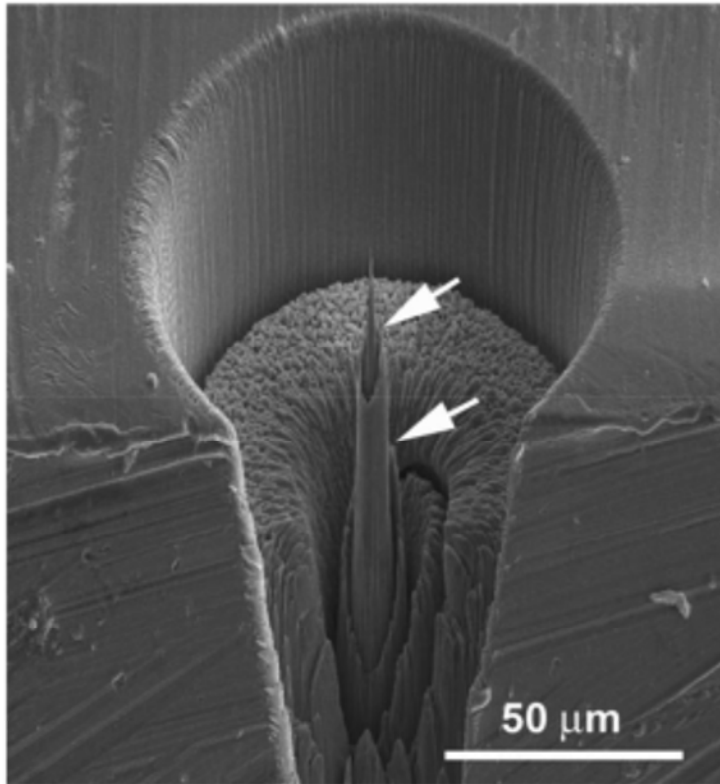
A "more complete" run would capture much more of the atomic chemistry of the oxide surface and of the near-surface bulk niobium



Present analyses

"More complete" analyses

Specimen preparation - focused ion beam (FIB) milling of "site-specific" LEAP specimens from niobium cavity materials



Possibility of centering a specimen on a region of interest (e.g., a grain boundary)

We will use the ANL Zeiss 1540XB dual-beam FIB to attempt "site-specific" specimen preparation

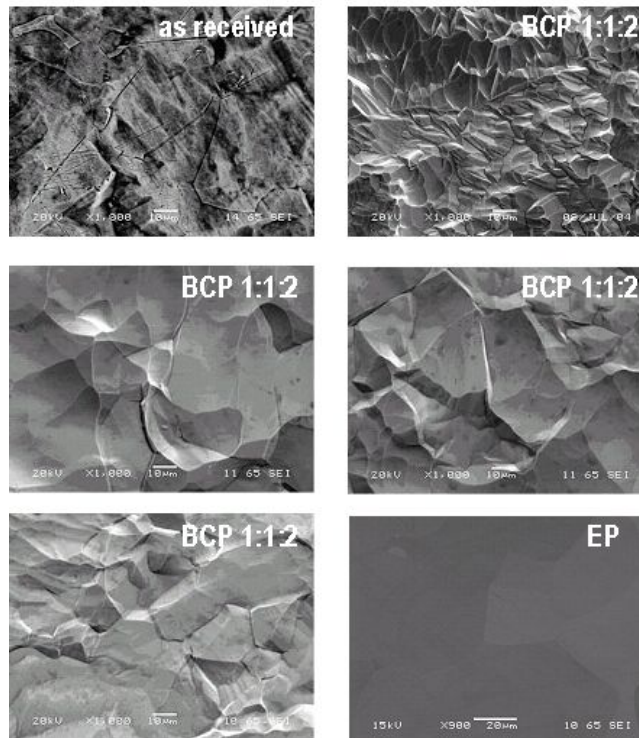
REFERENCE

Strategies for Fabricating Atom Probe Specimens with a Dual Beam FIB,
M.K. Miller, K.F. Russell and G.B. Thompson
Ultramicroscopy, 102 (2005) 287-298.

Studies of Nb cavity materials

- SEM micrographs from P. Bauer et al.

Surfaces:



C. Chapman, D. Hicks, C. Boffo

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